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Sub Data Sheet

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SERIAL NUMBER	FILING DATE	CLASS	GROUP ART UNIT	ATTORNEY DOCKET NO.
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CONTINUING DATA *none*

FOREIGN APPLICATIONS

JAPAN 2000-193104 08/27/2000
JAPAN 2000-229101 07/28/2000
JAPAN 2000-335934 11/02/2000
JAPAN 2001-11218 01/18/2001
JAPAN 2001-31901 02/08/2001
JAPAN 2001-31906 02/08/2001
JAPAN 2001-33599 02/09/2001
JAPAN 2001-35089 02/13/2001
JAPAN 2001-158662 05/28/2001
JAPAN 2001-162041 05/30/2001
JAPAN 2001-189304 06/22/2001

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

08/29/2001

Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS DRAWING	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Not other	JAPAN	50	60	13
Verified and Acknowledged	Attorney's Signature <i>Paul Brown</i>	Examiner's Signature			

ADDRESS

23850

TITLE

Inspection system by charged particle beam and method of manufacturing devices using the system

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